

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10601264	HILL ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Chawan, Sheela C	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	141, 312	9/22/07	SCC
358	498	9/22/07	SCC
399	205	9/22/07	SCC
355	57	9/22/07	SCC
250	234	9/22/07	SCC
ABOVE SEARCH UP- DATE.		9/22/07	SCC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
SEARCH EAST AND OTHER DATA BASE, SEE ATTACHED SEARCH HISTORY.	9/22/07	SCC
382/141,312.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	9/22/07	SCC
358/471,474, 494, 488, 509, 482, 296, 498.CCLS.	9/22/07	SCC
399/206,205,202,200.CCLS.	9/22/07	SCC
355/57,66,60,55, 71,51,69.CCLS.	9/22/07	SCC
"	9/22/07	SCC
362/227.CCLS.	9/22/07	SCC
"	9/22/07	SCC
250/234,235,559.01.CCLS.	9/22/07	SCC
INTERFERENCE SEARCH SEE THE SEARCH HISTORY PRINT OUT.	9/22/07	SCC
INVENTOR NAME SEARCH	9/22/07	SCC
SEARCH INSPEC OR IEEE DATA	9/22/07	SCC
ABOVE SEARCH UP-DATE.	9/22/07	SCC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	141, 312	9/22/07	SCC
358	498	9/22/07	SCC
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